## In the Specification:

Please amend the Specification such that the Abstract in its entirety reads as follows:

In <u>some aspects</u> a <u>first aspect</u>, a <u>first</u> method is provided for testing an integrated circuit (IC). The <u>first</u> method includes the steps of (1) selecting a bit from each of a plurality of memory arrays formed on an IC chip $_{7}$  (2) selecting one of the plurality of memory arrays $_{7}$  and  $_{3}$  storing the selected bit from the selected memory array. Numerous other aspects are provided.